



ATTY. DKT. 28951.5300

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Serial No.: 10/726,891

Confirmation No.: 4184

In re Application of:

Satoru KAMANO et al.

Group Art Unit: 2829

Filed: December 4, 2003

Examiner: Tung X. Nguyen

For: ANCILLARY EQUIPMENT FOR TESTING  
SEMICONDUCTOR INTEGRATED CIRCUIT

**AMENDMENT UNDER 37 CFR 1.111**

Mail Stop AF  
Commissioner for Patents  
Customer Window  
Randolph Building  
401 Dulany Street  
Alexandria, VA 22314

Sir:

In response to the Office Action mailed September 8, 2005 please amend the above-identified application as follows: